



# **RELIABILITY MONITOR SUMMARY**

**QUARTERLY SUMMARY, QUARTER 1, 1996**

**April 21, 1996**

**PERFORMED PER THE REQUIREMENTS OF 25-00008, RELIABILITY MONITOR PROGRAM SPECIFICATION.**

**ORIGINATOR:**

\_\_\_\_\_  
**MUOI VU  
QUALITY ENGINEER**

\_\_\_\_\_  
**DATE**

**APPROVED:**

\_\_\_\_\_  
**GEORGE PERREAULT  
RELIABILITY ENGINEERING MANAGER**

\_\_\_\_\_  
**DATE**



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## STANDARD STRESS TEST DESCRIPTIONS

Test	Description
HTOL	High Temp Op Life, 150°C, 5.75V
HTOL2	High Temp Op Life, 125°C, 5.75V
HTSSL	High Temp Steady State Life, 150°C, 5.75V
HTSSL2	High Temp Steady State Life, 125°C, 5.75V
DRET	Data Retention Test, Data Bake 165°C, Plastic
DRET2	Data Retention Test, Data Bake 250°C, Hermetic
PCT	Pressure Cooker Test, 121°C, 100% RH, No Bias
HAST	Hi-Accel Saturation Test, 140°C, 85% RH, 5.5V Bias
85/85	Hi-Accel Saturation Test, 85°C, 85V
TC	Temp Cycle, 125°C to -40°C
TC2	Temp Cycle, 150°C to -65°C
HTS	High Temp Storage, 165°C, No Bias



## WAFER FAB AREAS

FAB #	LOCATION
CA	SAN JOSE, CALIFORNIA
TX	ROUND ROCK, TEXAS
MN	BLOOMINGTON, MINNESOTA
FR	MHS, FRANCE

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## ASSEMBLY LOCATIONS

COMPANY/LOCATION	ID
Anam-Buchon/Korea	KOREA-A
Asat/Hongkong	ASAT-B
Cypress/USA	USA-C
Dynesem/Phillipine	PHIL-D
Cypress-Minesota/USA	USA-E
Astra/Indonesia	INDNS-F
Golden Altos/USA	USA-G
Hyundai/Korea	KOREA-H
Indy/USA	USA-I
Kyocera/Japan	JAPAN-K
Anam-Seoul/Korea	KOREA-L
Anam/Phillipine	PHIL-M
Omedata/Indonesia	INDNS-O
Pantronix/USA	USA-P
Anam-Bupyong/Korea	KOREA-Q
TSCM/Taiwan	TAIWAN-R
Chinkteik/Thailand	THLAND-S
OSE/Taiwan	TAIWAN-T
Unisem/Malaysia	MALAY-U
VLSI/USA	USA-V
Toshiba/USA	USA-W
Cypress Bangkok/Thailand	ALPHA-X
Alphatech/Thailand	ALPHA-Y

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### Description of Data Table Column Headings

Column Heading	Description of Column Contents
Prod Line	Manufacturing Division
Test	Common code for the stress performed. See table on previous page for detail.
Test Condition	Temp/humidity/bias conditions for the stress. See table on previous page for detail.
Device ID	Cypress manufacturing part number for specific type.
Date Code	Week in which the specific lot was sealed/molded.
Lot Number	Manufacturing (assembly) lot number of material stressed.
Function	Generic product family at Cypress.
Description	Brief description of device function.
Technology	Fabrication process technology. See Cypress Product Matrix for detail.
Process	Generic fabrication process.
Process Location	State where fabrication facility is located. See table on previous page for detail.
Pkg Material	Generic packaging material
Pkg Type	Common code for standard package configuration (PDIP=Plastic Dual-In-Line-Package).
Package Location	Country Location + Initial of assembly house (see table on previous page for detail).
# Pins	Pin count of package in which device is assembled.
Duration	Data Readpoint of stress. For Temp Cycle (TC)=Cycles; all other stresses=Hours.
# Tested	Quantity of devices submitted to this stress/test.
# Failed	Quantity of devices failing at this specific readpoint.
Fail Mode	Failure analysis results from this test, if any.



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Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Function	Description	Technology	Process	Wfr Loc	Pkg type	Assy Loc	No# Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
CPD	DRET	165C/NO BIAS	CY2291SC	95197	9524	13040(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	168	76	0	
															552	78	0	
					9528	13109(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	168	80	0	
															552	80	0	
					96061	9550 349524602	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	168	76	0	
															552	76	0	
	HAST	140C/3.8V 140C/5.5V	CY2254ASC CY2291SC	95521	9539	13151(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L27	CMOS	MN	SOIC	PHIL-M	28	128	45	0	
				95197	9523	13041(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	128	49	0	
					9528	13109(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	128	50	0	
	HTOL	150C/4.05V	CY2254ASC	96061	9542	349522690	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	128	45	0	
				95521	9539	13151(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L27	CMOS	MN	SOIC	PHIL-M	28	48	510	0	
															425	116	0	
		150C/5.5V	CY2291SC	95197	9524	13040(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	48	354	0	
															80	116	0	
															500	116	0	
															80	120	0	
															197	120	0	
															500	116	0	
															1000	116	0	
															2000	116	0	
					9528	13109(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	48	354	0	
															80	116	0	
															500	116	0	
					96061	9550 349524602	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	48	1000	0	
															80	116	0	
															500	116	0	
	HTSSL	150C/5.75V 150C/4.05V 150C/5.5V	CY2291SC CY2254ASC CY2291SC	95197	9525	13041(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	48	354	0	
				95521	9539	13151(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L27	CMOS	MN	SOIC	PHIL-M	28	168	75	0	1 EOS
				95197	9523	13041(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	80	76	0	
															168	76	0	
															80	76	0	
															168	76	0	
															80	76	0	
															168	76	0	
															168	76	0	
	LTOL	-45C/6.5V	CY2291SC	95197	9524	13040(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	500	47	0	
															1000	47	0	
	PCT	121C/100%RH	CY2291SC	95197	9523	13041(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	168	45	0	
	TC2	-65C TO 150C	CY2254ASC	95521	9539	13151(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	168	50	0	
			CY2291SC	95197	9523	13041(SWR)	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	PHIL-M	20	300	45	0	
															1000	45	0	
															300	49	0	
															1000	49	0	
															20	300	46	0
															1000	46	0	
															20	300	50	0
															1000	50	0	
															20	300	45	0
															1000	45	0	

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Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Function	Description	Technology	Process	Wfr Loc	Pkg type	Assy Loc	No# Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
DCD	HAST	140C/5.5V	CY7B8392-JC	96056	9604	519601220	ENET	TRANSCEIVER	BICMOS-SM1	BiCMOS	TX	PLCC	KOREA-A	28	128	45	0	
			CY7B923-JI	95481	9601	349525476	CHNL	HOTLink	BICMOS-SM1	BiCMOS	TX	PLCC	KOREA-A	28	128	50	0	
			CY7C025-JC	95226	9544	349522865	SPCM	8K x 16 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	KOREA-A	84	128	48	0	



HTOL	150C/5.75V	CY7C462-15JC	M53044	9503	349500589	SPCM	16Kx9 FIFO	SRAM/LOGIC-R21	CMOS	MN	PLCC	KOREA-A	28	128	81	0
		CY7C025-JC	95226	9544	349522865	SPCM	8K x 16 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	KOREA-A	84	48	522	0
														80	130	0
														500	130	0
HTOL2	125C/5.75V			9549	349524484	SPCM	8K x 16 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	KOREA-A	84	48	512	0
														80	120	0
														500	120	0
		CY7C433-15JCT	96031	9549	349524035	SPCM	4Kx9 FIFO	SRAM/LOGIC-R25	CMOS	MN	PLCC	KOREA-A	32	48	1174	0
HTSSL	150C/5.75V	CY7B145-35JI	M53036	9538	349519727	SPCM	8K x 9 DP	BICMOS-SM2	BiCMOS	TX	PLCC	KOREA-A	68	96	120	0
														500	120	0
														1000	120	0
														2000	120	0
PCT	121C/100%RH TC2 -65C TO 150C	CY7B8392-PC	96056	9546	519502466	ENET	TRANSCEIVER	BICMOS-SM1	BiCMOS	TX	PDIP	INDNS-O	16	48	1026	0
														80	146	0
														500	146	0
														80	76	0
TC2	150C/9.0V	CY7C025-JC	95226	9544	349522865	SPCM	8K x 16 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	KOREA-A	84	168	76	0
														80	80	0
														168	80	0
		CY7B8392-PC	96056	9546	519502466	ENET	TRANSCEIVER	BICMOS-SM1	BiCMOS	TX	PDIP	INDNS-O	16	80	76	0
TC2	150C/9.0V													168	76	0
		CY7C025-JC	95226	9544	349522865	SPCM	8K x 16 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	KOREA-A	84	168	45	0
		CY7B8392-JC	96056	9604	519601220	ENET	TRANSCEIVER	BICMOS-SM1	BiCMOS	TX	PLCC	KOREA-A	28	300	45	0
														1000	45	0
TC2	150C/9.0V	CY7B923-JI	95481	9601	349525476	CHNL	HOTLink	BICMOS-SM1	BiCMOS	TX	PLCC	KOREA-A	28	300	50	0
		CY7C025-AC	95226	9601	349525183	SPCM	8K x 16 DP	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	100	300	50	0
		CY7C025-JC	95226	9549	349524484	SPCM	8K x 16 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	KOREA-A	84	300	48	0



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MPD	HAST	140C/5.5V	CY7C109-20VC	95457	9543	349522649	COMDTY	128K x 8	SRAM/LOGIC-R25	CMOS	MN	SOJ	KOREA-L	32	128	48	0		
			CY7C199-20VIT	M54002	9549	219518163	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	128	80	0		
			CY7C199-VC	M53019	9532	219511350	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-Y	28	128	79	1	1 PARTICLE	
				M53028	9536	219513029	COMDTY	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	128	80	4	4 POLY FUSES	
			CY7C199-ZC	95516	9533	349510964	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	128	48	0		
						349510965	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	128	48	0		
			CY7C109-20VC	95423	9539	349521201	COMDTY	128K x 8	SRAM/LOGIC-R25	CMOS	MN	SOJ	KOREA-L	32	48	496	0	4 EOS	
				95457	9543	349522649	COMDTY	128K x 8	SRAM/LOGIC-R25	CMOS	MN	SOJ	KOREA-L	32	80	118	0		
															500	118	0		
	HTOL	150C/5.75V	CY7C185-VC	96024	9602	219600563	COMDTY	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	48	5179	0		
						219600565	COMDTY	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	48	5280	0		
						219600567	COMDTY	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	48	5191	0		
			CY7C194-VC	95471	9545	519501923	COMDTY	64K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	24	80	116	0		
			CY7C199-VC	95423	9538	219513829	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	48	503	0	1 EOS	
															80	120	0		
															500	120	0		
						9540	349521454	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	48	505	0	
															80	120	0		
															500	120	0		
			HTOL2	95423	9541	349522118	COMDTY	128K x 8	SRAM/LOGIC-R25	CMOS	MN	SOJ	KOREA-L	32	96	500	0		
															168	232	1	1 TOPSIDE CRACKS	
															500	231	0		
															1000	231	0		
			HTS	95516	9533	349510965	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	336	48	0		
															500	48	0		
															1000	48	0		
			HTSSL	95457	9543	349522649	COMDTY	128K x 8	SRAM/LOGIC-R25	CMOS	MN	SOJ	KOREA-L	32	80	78	0		
															168	78	0		
			CY7C194-VC	95471	9545	519501923	COMDTY	64K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	24	80	76	0		
															168	76	0		
			HTSSL2	M53005	9527	219509711	COMDTY	32K x 8	SRAM/LOGIC-R3	CMOS	CA	SOJ	ALPHA-X	28	96	120	0		
															168	120	0		
															500	119	0		
															1000	119	0		
															2000	119	0		
	LTOL	-45C/6.5V	CY7C109-20VC	95457	9543	349522649	COMDTY	128K x 8	SRAM/LOGIC-R25	CMOS	MN	SOJ	KOREA-L	32	500	48	0		
															1000	48	0		
			CY7C194-VC	95471	9545	519501923	COMDTY	64K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	24	500	48	0		
	PCT	121C/100%RH													1000	48	0		
			CY7C199-20VIT	M54003	9549	219518163	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	96	80	0		
															168	80	0		
			CY7C199-VC	M54021	9603	519600648	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	96	80	0		



Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Func-tion	Descr Description	Technology	Pro-cess	Wfr Loc	Pkg type	Assy Loc	No# Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
MPD	T/S	-55C TO 150C	CY7C199-ZC	95516	9533	349510965	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	100	48	0	
	TC2	-65C TO 150C	CY7C1031-JC	95312	9534	349518285	SYNCHR	64K x 18	SRAM/LOGIC-R3	CMOS	MN	PLCC	INDNS-O	52	200	48	0	
			CY7C185-VC	96036	9602	219600563	COMDTY	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	1000	45	0	
						219600563/	COMDTY	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	300	54	0	
						219600565	COMDTY	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	300	54	0	
															1000	54	0	
						219600567	COMDTY	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	300	54	0	
															1000	54	0	
				96058	9604	519600917	COMDTY	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	300	54	0	
						519600974	COMDTY	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	300	47	0	
					9608	519602323	COMDTY	SML/64K	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	300	54	0	
			CY7C199-15VC	M53015	9536	349519413	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	28	300	50	8	8 TOPSIDE CRACKS
			CY7C199-PC	M53021	9541	219515020	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	PDIP	ALPHA-X	28	300	50	0	
															1000	50	0	
			CY7C199-VC	95289	9534	219512438	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	300	50	0	
															1000	50	0	
						219512439	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	300	50	0	
															1000	50	0	
						219512441	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	300	50	0	
															1000	50	0	
				M53018	9532	219511350	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-Y	28	300	50	0	
				M53041	9529	349514101	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-F	28	300	50	2	2 TOPSIDE CRACKS
			M53034	9538	349520839	COMDTY	32K x 8	SRAM/LOGIC-R21	CMOS	TX	SOJ	INDNS-O	28	300	50	5	5 TOPSIDE CRACKS	
			CY7C199-VI	95516	9533	349510964	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	300	48	0	
			CY7C199-ZC			349510965	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	300	48	0	
	TEV	0 READ POINT	CY7C199-20VCT	M54014	9551	519504071	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	INDNS-O	28	-5	118	0	
															25	118	0	
															85	118	0	





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Prod line	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Func- tion	Descr Description	Technology	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No# Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
PPD	DRET	165C/NO BIAS	CY27C512-WC	95517	9529	219510327	PROM	64K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	28	552	76	0	
			CY7C342B-JC	95514	9344	70059	MAX	REPROG. PAL	FAMOS-P26	CMOS	TX	PLCC	KOREA-A	68	168	77	0	
															500	77	0	
						70060	MAX	REPROG. PAL	FAMOS-P26	CMOS	TX	PLCC	KOREA-A	68	1000	77	0	
															168	45	0	
															500	45	0	
															1000	45	0	
			CY7C371-JC	M53012	9535	349518118	FLASH	32-MCEL FL	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	44	336	80	0	
															1000	80	0	
	DRET2	250C/NO BIAS	CY27C512-WC	95517	9543	219515923	PROM	64K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	28	96	76	0	
			CY7C342B-HC	95514	N/A	10323	MAX	REPROG. PAL	FAMOS-P26	CMOS	CA	CERQ	KOREA-A	68	168	76	0	
			PALC22V10B-DMB	95426	9539	219514405	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	CERD	ALPHA-X	24	96	78	0	
	GRP-C HAST	150C/5.75V 130C/5.5V	PALC22V10B-DMB	95426	9539	219514405	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	CERD	ALPHA-X	24	500	118	0	
			CY7C374-AC	95224	9517	349505456L	FLASH	128 MCEL FL	FLASH-FL22D	CMOS	CA	TQFP	KOREA-Q	100	64	24	0	
															128	24	0	
			CY7C386A-JC	95421	9550	2545823	FPGA	4K GATE	FAMOS-VL26D	CMOS	TX	PLCC	KOREA-A	84	128	50	0	
															256	50	0	
			CY7C388A-NC	95393	9550	2541315	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP	KOREA-A	208	256	49	0	1 EOS
		140C/5.5V	CY27C010-PC	96022	9601	349525180	PROM	128K x 8	FAMOS-P26	CMOS	TX	PDIP	KOREA-H	32	128	46	0	
				M54004	9547	349523760	PROM	128K x 8	FAMOS-P26	CMOS	TX	PDIP	KOREA-H	32	128	77	0	
			CY74FCT16952TPA	96103	9519	3538802	FCT	16 BIT	SRAM/LOGIC-L27	CMOS	MN	TSSO	TAIWAN-T	56	128	47	0	
			CY74FCT16952TPV	96035	9603	3538802	FCT	16 BIT	SRAM/LOGIC-L27	CMOS	MN	SSOP	TAIWAN-T	56	128	48	0	
				96103	9603	3538802	FCT	16 BIIT	SRAM/LOGIC-L27	CMOS	MN	SSOP	TAIWAN-T	56	128	48	0	
			CY7C342B-JC	95514	9602	349525756	MAX	REPROG. PAL	FAMOS-P26	CMOS	TX	PLCC	KOREA-A	68	128	44	0	1 EOS
					9603	349600026	MAX	REPROG. PAL	FAMOS-P26	CMOS	TX	PLCC	KOREA-A	68	128	48	0	
															256	48	0	
			CY7C374-AC	95224	9505	349415643	FLASH	128 MCEL FL	FLASH-FL22D	CMOS	CA	TQFP	KOREA-Q	100	128	24	0	
			CY7C384A-JC	95283	9528	2522774	FPGA	2K GATE	FAMOS-VL26D	CMOS	TX	PLCC	KOREA-A	84	128	42	0	
					9536	2528491	FPGA	2K GATE	FAMOS-VL26D	CMOS	TX	PLCC	KOREA-A	84	128	45	0	
			CY7C388A-NC	95393	9602	2543561	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP	KOREA-A	208	256	52	0	
			PALC22V10-PC	95287	9529	349514916	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	PDIP	INDNS-O	24	128	51	0	
			PALC22V10B-JC	95287	9541	519500676	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	PLCC	INDNS-O	28	128	97	0	
					9604	519601180	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	PLCC	INDNS-O	28	128	48	0	
					96041	519500676	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	PLCC	INDNS-O	28	128	49	0	
			PALC22V10L-PI	M54009	9544	519501821	PLD	REPROG. PAL	FAMOS-P13	CMOS	TX	PDIP	INDNS-O	24	128	79	0	
			PALCE16V8L-JC	96023	9601	519504486	PLD	FLASH ERAS.	FLASH-FL22D	CMOS	TX	PLCC	INDNS-O	20	128	45	1	1 PACKAGING/ASSY PROB
			PALCE20V8L-JC	96037	9604	519600904	PLD	FLASH ERAS.	FLASH-FL28D	CMOS	TX	PLCC	INDNS-O	28	128	48	0	



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PPD	HTOL	150C/5.5V	CY27H010-WC CY7C384A-JC	95358	9533	219511938	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	32	48	500	0	
				95283	9528	2522774	FPGA	2K GATE	FAMOS-VL26D	CMOS	TX	PLCC	KOREA-A	84	48	100	0	
															168	76	0	
															500	76	0	
					9536	2528491	FPGA	2K GATE	FAMOS-VL26D	CMOS	TX	PLCC	KOREA-A	84	48	100	0	
															168	76	0	
															500	76	0	
					9602	349525384	FPGA	2K GATE	FAMOS-VL26D	CMOS	TX	PLCC	KOREA-A	84	48	10	0	
															168	10	0	
															500	10	0	
					9605	2528611	FPGA	2K GATE	FAMOS-VL26D	CMOS	TX	PLCC	KOREA-A	84	48	100	0	
															168	76	0	
															500	76	0	
			CY7C386A-JC	95421	9550	2545823	FPGA	4K GATE	FAMOS-VL26D	CMOS	TX	PLCC	KOREA-A	84	48	250	0	
			CY7C388A-NC	95393	9550	2541315	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP	KOREA-A	208	168	90	0	
															48	20	0	
															168	20	0	
															500	20	0	
															48	76	0	1 EOS
															168	51	0	
															48	34	0	
															168	34	0	
															500	34	0	
						2543819	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP	KOREA-A	208	48	10	0	
															48	67	0	1 EOS
															168	62	0	
															500	62	0	
		150C/5.75V	CY27C512-WC	95517	9524	2546972	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP	KOREA-A	208	48	72	0	
						219518532	PROM	64K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	28	48	388	0	
						219510326	PROM	64K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	28	48	10	0	
			CY27H010-WC	96022	9543	219515923	PROM	64K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	28	48	901	0	2 EOS
						219518589	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	32	48	981	0	15 EOS
															80	116	0	
															500	116	0	
															56	184	46	0
															56	184	46	0
															24	48	28	0
															80	28	0	
															80	120	0	
															500	120	0	
			CY7C342B-JC	95514	9525	349511336	MAX	REPROG. PAL	FAMOS-P26	CMOS	TX	PLCC	KOREA-A	68	80	120	0	
			CY7C388A-NC	95393	9602	2543561	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP	KOREA-A	208	500	51	0	



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PPD	HTOL	150C/5.75V	PALC22V10-PC	95287	9529	349514916	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	PDIP	INDNS-O	24	48	510	0	
															80	119	0	
															500	119	0	
															1000	119	0	
															2000	116	0	
			PALC22V10B-DMB	95426	9539	219514405	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	CERD	ALPHA-X	24	80	118	0	
															184	48	0	
			PALCE16V8L-JC	96023	9601	519504486	PLD	FLASH ERAS.	FLASH-FL22D	CMOS	TX	PLCC	INDNS-O	20	48	1011	0	
															80	125	0	
															500	118	0	
			PALCE20V8L-JC	96037	9604	519600904	PLD	FLASH ERAS.	FLASH-FL28D	CMOS	TX	PLCC	INDNS-O	28	48	1011	0	
															80	117	0	
															500	117	0	
	HTOL2	125C/5.75V	CY7C342-JC	96052	9602		MAX	REPROG. PAL	FAMOS-P20	CMOS	TX	PLCC	USA-C	68	72	30	0	
						13272 (SWR)	MAX	REPROG. PAL	FAMOS-P20	CMOS	TX	PLCC	USA-C	68	168	30	0	
															168	79	0	
			CY7C342B-HC	95514	N/A	10323	MAX	REPROG. PAL	FAMOS-P26	CMOS	CA	CERQ	KOREA-A	68	336	79	0	
															168	10	0	
															1000	10	0	
			CY7C342B-JC	95514	9524	13088 (SWR)	MAX	REPROG. PAL	FAMOS-P26	CMOS	TX	PLCC	KOREA-A	68	140	120	0	
															750	118	0	1 EOS
			CY7C371-JC	M52038	9523	349510044	FLASH	32-MCEL FL	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	44	96	77	0	
															500	77	0	
															1000	77	0	
															1500	76	0	
															2000	76	0	
			CY7C374-JC	95491	9528	349513771	FLASH	128 MCEL FL	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	84	96	120	0	
					9529	349514424	FLASH	128 MCEL FL	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	84	96	214	0	
						349514425	FLASH	128 MCEL FL	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	84	96	121	0	
	HTS	165C/NO BIAS	CY74FCT16952TPV	96035	9603	3538802	FCT	16 BIT	SRAM/LOGIC-L27	CMOS	MN	SSOP	TAIWAN-T	56	336	46	0	
															500	46	0	
															1000	45	0	
				96103	9603	3538802	FCT	16 BIT	SRAM/LOGIC-L27	CMOS	MN	SSOP	TAIWAN-T	56	336	46	0	
															500	46	0	
			CY7C388A-NC	95393	9602	2543561	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP	KOREA-A	208	336	50	0	
	HTSSL	150C/5.75V	CY27C512-WC	95517	9543	219515923	PROM	64K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	28	80	76	0	
															168	75	0	1 EOS
			CY27H010-WC	96022	9551	219518589	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	32	80	76	0	
															168	76	0	
			CY7C342B-JC	95514	9524	13088 (SWR)	MAX	REPROG. PAL	FAMOS-P26	CMOS	TX	PLCC	KOREA-A	68	80	80	0	
					9525	349511336	MAX	REPROG. PAL	FAMOS-P26	CMOS	TX	PLCC	KOREA-A	68	80	80	0	
															168	80	0	
			PALC22V10-PC	95287	9529	349514916	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	PDIP	INDNS-O	24	80	80	0	
															168	80	0	
	HTSSL2	125C/5.75V	CY7C342-35JC	M52018	9521	349509096	MAX	REPROG. PAL	FAMOS-P20	CMOS	TX	PLCC	KOREA-A	68	96	120	0	
															500	120	0	
															1000	120	0	
															2000	118	0	2 EOS
			CY7C371-JC	M53011	9535	349518118	FLASH	32-MCEL FL	FLASH-FL22D	CMOS	CA	PLCC	KOREA-A	44	2000	80	0	

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PPD	LTOL	-55C/6.0V	CY7C384A-JC	95283	9536	2528491	FPGA	2K GATE	FAMOS-VL26D	CMOS	TX	PLCC	KOREA-A	84	168	50	0	
															500	50	0	
						9605	2528611	FPGA	2K GATE	CMOS	TX	PLCC	KOREA-A	84	168	50	0	
															500	50	0	



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PCT	121C/100%RH	CY7C388A-NC	95393	9544 2534315	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP KOREA-A	208	168	49	0	1	EOS
				9550 2541315	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP KOREA-A	208	500	46	0		
												168	50	0	1	EOS
												500	49	0		
		CY7C342B-JC	95514	9602 349525756	MAX	REPROG. PAL	FAMOS-P26	CMOS	TX	PLCC KOREA-A	68	168	48	0		
				9603 349600026	MAX	REPROG. PAL	FAMOS-P26	CMOS	TX	PLCC KOREA-A	68	288	48	0		
												168	51	0		
												288	51	0		
		CY7C384A-JC	95283	9528 2522774	FPGA	2K GATE	FAMOS-VL26D	CMOS	TX	PLCC KOREA-A	84	168	45	0		
		CY7C388A-NC	95393	9550 2541315	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP KOREA-A	208	168	48	0		
T/S	-55C TO 150C	PALC22V10-PC	95287	9529 349514916	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	PDIP INDNS-O	24	168	51	0		
												288	51	0		
		PALC22V10B-JC	95287	9541 519500676	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	PLCC INDNS-O	28	168	46	0		
												288	46	0		
		PALC22V10L-PI	M54008	9544 519501821	PLD	REPROG. PAL	FAMOS-P13	CMOS	TX	PDIP INDNS-O	24	96	78	0	1	EOS
												168	76	0		
		CY74FCT16952TPV	96035	9519 3538802	FCT	16 BIT	SRAM/LOGIC-L27	CMOS	MN	SSOP TAIWAN-T	56	100	46	0		
				96103 9519 3538802	FCT	16 BIT	SRAM/LOGIC-L27	CMOS	MN	SSOP TAIWAN-T	56	200	46	0		
												200	46	0		
												200	46	0		
TC	-40C TO 125C	CY7C374-AC	95224	9505 349415643	FLASH	128 MCEL FL	FLASH-FL22D	CMOS	CA	TQFP KOREA-Q	100	500	48	0		
TC2	-65C TO 150C	CY27C512-WC	95517	9524 219518532	PROM	64K x 8	FAMOS-P26	CMOS	TX	WCER ALPHA-X	28	1500	48	0		
				9543 219515923	PROM	64K x 8	FAMOS-P26	CMOS	TX	WCER ALPHA-X	28	100	45	0		
												1000	45	0		
		CY27H010-WC	96022	9551 219518589	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER ALPHA-X	32	100	45	0		
												1000	45	0		
		CY74FCT16952TPA	96035	9519 3538802	FCT	16 BIT	SRAM/LOGIC-L27	CMOS	MN	TSSO TAIWAN-T	56	300	47	0		
			96103	9519 3538802	FCT	16 BIT	SRAM/LOGIC-L27	CMOS	MN	TSSO TAIWAN-T	56	1000	93	0		
												45	0			
		CY74FCT16952TPV	96035	9519 3538802	FCT	16 BIT	SRAM/LOGIC-L27	CMOS	MN	SSOP TAIWAN-T	56	300	46	0		
			96103	9519 3538802	FCT	16 BIT	SRAM/LOGIC-L27	CMOS	MN	SSOP TAIWAN-T	56	1000	46	0		
		CY7C342B-JC	95514	9602 349525756	MAX	REPROG. PAL	FAMOS-P26	CMOS	TX	PLCC KOREA-A	68	300	47	0		
				9603 349600026	MAX	REPROG. PAL	FAMOS-P26	CMOS	TX	PLCC KOREA-A	68	500	47	0		
												300	51	0		
												500	51	0		
		CY7C371-JC	M52031	9515 349505535	FLASH	32-MCEL FL	FLASH-FL22D	CMOS	CA	PLCC KOREA-A	44	1000	50	0		
			M52040	9523 349510044	FLASH	32-MCEL FL	FLASH-FL22D	CMOS	CA	PLCC KOREA-A	44	300	45	0		
			M53013	9535 349518118	FLASH	32-MCEL FL	FLASH-FL22D	CMOS	CA	PLCC KOREA-A	44	300	49	0		
		CY7C384A-JC	95283	9528 2522774	FPGA	2K GATE	FAMOS-VL26D	CMOS	TX	PLCC KOREA-A	84	300	45	0		
				9536 2528491	FPGA	2K GATE	FAMOS-VL26D	CMOS	TX	PLCC KOREA-A	84	300	45	0		
		CY7C386A-JC	95421	9550 2545823	FPGA	4K GATE	FAMOS-VL26D	CMOS	TX	PLCC KOREA-A	84	300	50	0		



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PPD	TC2	-65C TO 150C	CY7C388A-NC	95393	9545	2534315	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP	KOREA-A	208	300	45	0	
					9550	2541315	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP	KOREA-A	208	300	48	0	
					9602	2543561	FPGA	8K GATE	FAMOS-VL26D	CMOS	TX	PQFP	KOREA-A	208	300	53	0	
			PALC22V10-PC	95287	9529	349514916	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	PDIP	INDNS-O	24	300	51	0	
																1000	51	0
																24	100	48
			PALC22V10B-DMB	95426	9539	219514405	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	CERD	ALPHA-X	24	1000	48	0	
			PALC22V10B-JC	95287	9541	519500676	PLD	REPROG. PAL	FAMOS-P20	CMOS	TX	PLCC	INDNS-O	28	300	46	0	
																1000	46	0
																24	300	49
			PALC22V10L-PI	M54011	9544	519501821	PLD	REPROG. PAL	FAMOS-P13	CMOS	TX	PDIP	INDNS-O	24	1000	49	0	
TEV	0 READ POINT		PALCE16V8L-JC	96023	9601	519504486	PLD	FLASH ERAS.	FLASH-FL22D	CMOS	TX	PLCC	INDNS-O	20	300	45	0	
			PALCE20V8L-JC	96037	9604	519600904	PLD	FLASH ERAS.	FLASH-FL28D	CMOS	TX	PLCC	INDNS-O	28	300	45	0	
																1000	45	0
																28	300	48
			PALC22V10L-PI	M54005	9544	519501821	PLD	REPROG. PAL	FAMOS-P13	CMOS	TX	PDIP	INDNS-O	24	1000	48	0	
																-5	120	0
																25	120	0
																85	120	0